In re the Application of

Inventors:

Kenichiro SHINOI, et al.

Application No.:

10/542,611

Filed:

July 18, 2005

For: NOV 16 2006

ACCURACY MEASUREMENT APPARATUS AND ACCURACY MEASUREMENT METHOD FOR CHANNEL QUALITY REPORT

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner of Patents Washington, DC 20231

Dear Sir:

Pursuant to Rules 56 and 99, Applicants hereby call the attention of the Patent Office to the art listed on the attached Form PTO 1449. This reference was cited in a Korean Office Action dated September 25, 2006 (copy attached). US '195 corresponds to KR '333.

Applicants present this art so that the Patent Office may, in first instance, determine any relevancy thereof to the presently claimed invention, see Beckman Instruments, Inc. v. Chemtronics, Inc., 439 F.2d 1369, 1380, 165 USPQ 355, 364 (5th Cir. 1970). Also see Patent Office Rules 104 and 106. Applicants respectfully request that this art be expressly considered during the prosecution of this application and made of record herein and appear among the "References Cited" on any patent to issue herefrom.

Respectfully submitted,

Date: November 16, 2006

Jame's E. Ledbetter Registration No. 28,732

JEL/ejw

ATTORNEY DOCKET NO. L9289.05161

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EXAMINER: Initial if citation is considered, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.